Abstracts

High Spatial Resolution Dielectric Constant Uniformity Measurements Using Microstrip Resonant Probes

M.S. Wang, S. Bothra, J.M. Borrego and K.W. Kristal. "High Spatial Resolution Dielectric Constant Uniformity Measurements Using Microstrip Resonant Probes." 1990 MTT-S International Microwave Symposium Digest 90.3 (1990 Vol. III [MWSYM]): 1121-1124.

In this paper we present the use of evanescent fields of apertures in microstrip resonant probes for measuring dielectric constant uniformity with high spatial resolution. The accuracy we have achieved in dielectric constant measurement at 10 GHz is better than 2% using apertures as small as 0.030" X 0.010" in size.

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